## Notice of References Cited Application/Control No. 10/688,145 Examiner Sam K. Ahn Applicant(s)/Patent Under Reexamination LI ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,295,023 B1	09-2001	Bloebaum, Leland Scott	342/357.06
*	В	US-6,628,631 B1	09-2003	Mazawa et al.	370/331
*	С	US-2002/0136278 A1	09-2002	Nakamura et al.	375/148
*	D	US-2003/0067967 A1	04-2003	Miyoshi et al.	375/148
*	Е	US-2004/0017843 A1	01-2004	Fitton et al.	375/148
*	F	US-2004/0071199 A1	04-2004	Boesel et al.	375/150
*	G	US-2005/0277419 A1	12-2005	Takano et al.	455/442
	Н	US-			
	1	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
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